Supplementary Information

Photocatalytic double-sided adhesives: Preparation, photocatalytic

degradation of dye solution and durable performance

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1. X-ray diffraction (XRD) were examined on an X-ray diffractometer (X'Pert PRO,

PANalytical Co., the Netherlands) coupled with Cu Kα radiation (1.5406 Å).



Fig. S1 XRD patterns of photocatalysts.

2. High-resolution transmission electron microscope (HR-TEM) images were observed by a TEM (Tecnai G220, FEI, USA) with an accelerating voltage of 200 kV.



Fig. S2 TEM images of g-C₃N₄ (a), P25 TiO₂ (b) and TCN (c); HR-TEM image of

TCN (d).

3.



Fig. S3 Thickness of DSA